

N-Channel 800 V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)@T _j (max)	$R_{DS(on)}$ (m Ω)(Typ.)	I _D (A)	Q _g (Typ.)		
850	150 at V _{GS} = 10 V	18	54.7 nC		

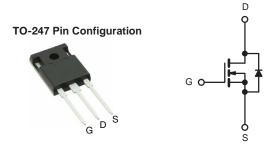




- DT-SJ Power MOSFET
- 100 % Rg and UIS tested
- $\bullet \ \, \text{Low} \,\, \text{R}_{\text{DS(ON)}} \textbf{x} \text{FOM} \\$
- · Extremely low switching loss
- · Excellent stability and uniformity

APPLICATIONS

- PC power
- Telecom power
- · Server power
- LED Light
- EV Charger



Top View N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	800	V	
Gate-Source Voltage		V _{GS}	± 30	7 v	
Continuous Drain Current (T _J = 150 °C) ^a	T _C = 25 °C	1	18		
	T _C = 100 °C	I _D	11.4	A	
Pulsed Drain Current ^b		I _{DM}	54		
Single Avalanche Energye		E _{AS}	662	mJ	
Maximum Davier Dissipations	T _C = 25 °C	D	219	W	
Maximum Power Dissipation ^c	T _C = 100 °C	P _D	87.6	VV	
Operating Junction and Storage Temperature Range		T _J , T _{stq}	-55 to +150	°C	

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	LIMIT	UNIT		
Junction-to-Ambient (PCB Mount) ^d	R _{thJA}	62	°C/W		
Junction-to-Case (Drain)	R _{thJC}	0.57	G/VV		

Notes

- a. Calculated continuous current based on maximum allowablejunction temperature.
- b. Repetitive rating; pulse width limited by max. junction temperature.
- c. Pd is based on max. junction temperature, using junction-case thermal resistance.
- d. The value of R_{0JA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper,in a still air environment with Ta=25 °C.
- e. V_{DD} =100 V, V_{GS} =10 V, L=75mH, starting T_j =25 °C.



SPECIFICATIONS (T _J = 25 °C, unless otherwise noted) PARAMETER SYMBOL TEST CONDITIONS MIN.						UNIT	
Static	STIMBUL	TEST CONDITIONS	IVIIIV.	TYP.	MAX.	UNIT	
			800	1			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V	
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.9	-	4		
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 30 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	10	μΑ	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 9 \text{ A}$	-	150	190	mΩ	
	DO(OII)	V_{GS} = 10 V, I_D = 9 A, T_j =150 °C	ı	434	-	1112.2	
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 50 \text{ V}, I_{D} = 9 \text{ A}$	ı	15	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	2718	-		
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 50 \text{ V}, f = 100 \text{ KHz}$	-	120	-	pF	
Reverse Transfer Capacitance	C _{rss}		-	5.2	-		
Total Gate Charge ^c	Qg		-	54.7	-		
Gate-Source Charge ^c	Q _{gs}	$V_{DS} = 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	14	-	nC	
Gate-Drain Charge ^c	Q_{gd}		1	5.5	-		
Gate Resistance	R_g	f = 1 MHz	-	1.6	-	Ω	
Turn-On Delay Time ^c	t _{d(on)}		-	47	-		
Rise Time ^c	t _r	$V_{DD} = 400 \text{ V}, I_{D} = 10 \text{ A},$	-	26	-		
Turn-Off Delay Time ^c	t _{d(off)}	$V_{GEN} = 10 \text{ V}, R_g = 2 \Omega$	-	147	-	ns	
Fall Time c	t _f		-	18	-		
Drain-Source Body Diode Ratings ar	nd Characteris	stics ^b (T _C = 25 °C)					
Continuous Source Current	I _S	T _C = 25 °C	-	-	18	Α	
Pulsed Current (t = 100 μs)	I _{SM}		-	-	54	Α	
Forward Voltage ^a	V _{SD}	I _S = 18 A, V _{GS} = 0 V	-	-	1.3	V	
Reverse Recovery Time	t _{rr}		-	374	-	ns	
Reverse Recovery Charge	Q _{rr}	I _S = 10 A, di/dt = 100 A/μs	-	5.9	-	μC	
Peak reverse recovery current	I _{rrm}		_	28.6	_	A	

Notes

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)

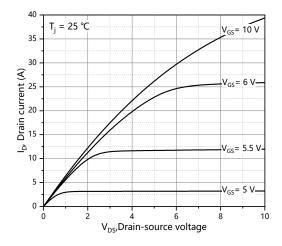


Figure 1. Typ. output characteristics

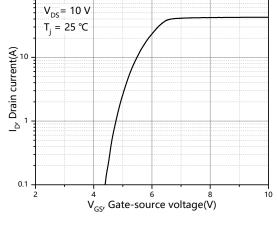


Figure 2. Typ. transfer characteristics

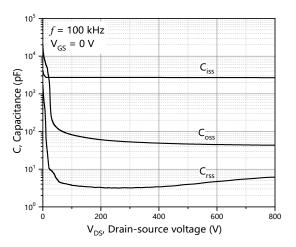


Figure 3. Typ. capacitances

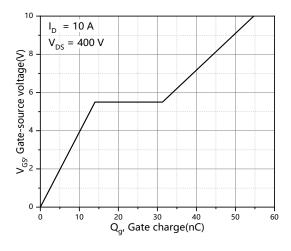


Figure 4. Typ. gate charge

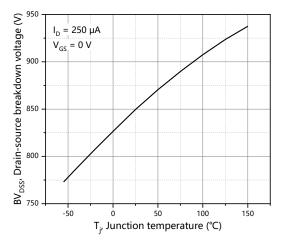


Figure 5. Drain-source breakdown voltage

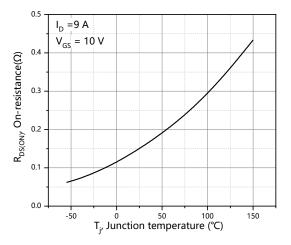
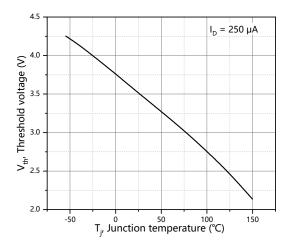


Figure 6. Drain-source on-state resistance



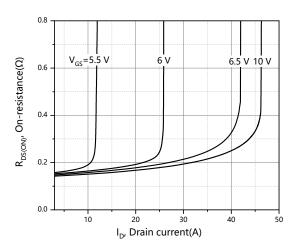
TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)



T_i = 25 ℃

Figure 7. Threshold voltage

Figure 8. Forward characteristic of body diode



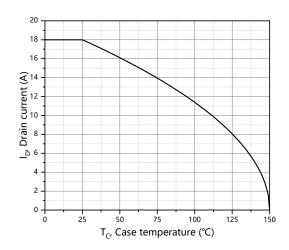
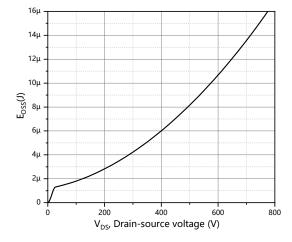


Figure 9. Drain-source on-state resistance

Figure 10. Drain current



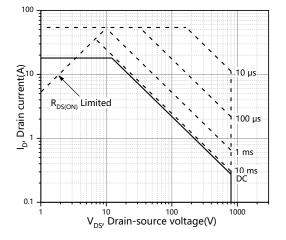


Figure 11. Typ. coss stored energy

Figure 12. Safe operation area Tc=25°C

TYPICAL CHARACTERISTICS ($T_A = 25 \, ^{\circ}\text{C}$, unless otherwise noted)

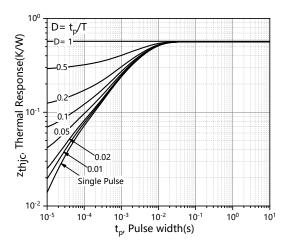
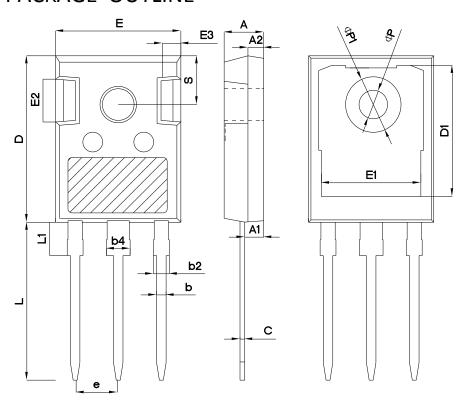


Figure 13. Max. transient thermal impedance



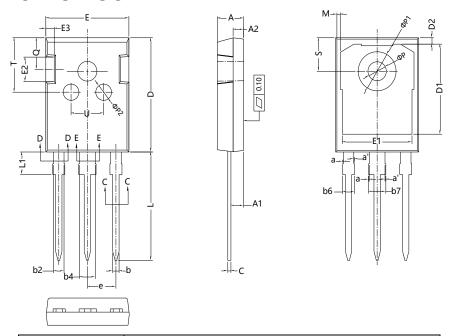
TO-247-P PACKAGE OUTLINE



Symbol	mm			
	Min	Nom	Max	
А	4.80	5.00	5.20	
A1	2.21	2.41	2.59	
A2	1.85	2.00	2.15	
b	1.11	1.21	1.36	
b2	1.91	2.01	2.21	
b4	2.91	3.01	3.21	
С	0.51	0.61	0.75	
D	20.80	21.00	21.30	
D1	16.25	16.55	16.85	
Е	15.50	15.80	16.10	
E1	13.00	13.30	13.60	
E2	4.80	5.00	5.20	
E3	2.30	2.50	2.70	
е	5.44BSC			
L	19.82	19.92	20.22	
L1	-	-	4.30	
ФР	3.40	3.60	3.80	
ФР1	-	-	7.30	
S	6.15BSC			



TO-247-J PACKAGE OUTLINE



Symbol		mm	
	Min	Nom	Max
Α	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
а	0.00	-	0.15
a [,]	0.00	-	0.15
b	1.16	•	1.26
b2	1.96	-	2.06
b4	2.96	-	3.06
b6	-	-	2.25
b7	-	-	3.25
С	0.59	-	0.66
c1	0.58	0.60	0.62
D	20.90	21.00	21.10
D1	16.25	16.55	16.85
D2	1.05	1.17	1.35
E	15.70	15.80	15.90
E1	13.10	13.30	13.50
E2	4.40	4.50	4.60
E3	1.50	1.60	1.70
е	5.436 BSC		
L	19.80	19.92	20.10
L1	-	-	4.30
M	0.35	-	0.95
Р	3.40	3.50	3.60
P1	7.00	-	7.40
P2	2.40	2.5	2.6
Q	5.60	-	6.0
S	6.05	6.15	6.25
Т	9.8	-	10.20
U	6.00	-	6.40





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